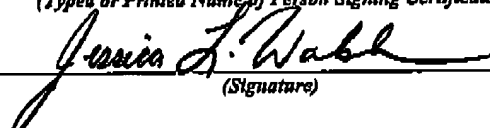


CERTIFICATE OF TRANSMISSION BY FACSIMILE (37 CFR 1.8) Applicant(s): S. SUNDAR KUMAR IYER ET AL.			Docket No. FIS920000372US1	
Serial No. 09/878,556	Filing Date 06/11/2001	Examiner J. CHEN	Group Art Unit 2813	
Invention: METHOD FOR FORMING VARIABLE OXIDE THICKNESS ACROSS SEMICONDUCTOR CHIPS				
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I hereby certify that this _____ <u>Response to Office Action</u> <i>(Identify type of correspondence)</i> is being facsimile transmitted to the United States Patent and Trademark Office (Fax. No. <u>703-872-9306</u>) on <u>February 12, 2004</u> <i>(Date)</i>				
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Applicant:	S. SUNDAR KUMAR IYER, ET AL.)	
)	Group Art Unit: 2813
Serial No.:	09/878,556)	
)	
Filed:	June 11, 2001)	Examiner: Chen, J.
)	
For:	METHOD OF FORMING VARIABLE)	
	OXIDE THICKNESS ACROSS)	Confirmation No.: 3210
	SEMICONDUCTOR CHIPS)	

RESPONSE TO OFFICE ACTION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In response to the Office Action mailed January 12, 2004, the Applicants submit the following remarks: